



RAM Mounts Testing Summary

RAM® Key Locking Dock for Samsung Tab Active5 & 3

Products Covered

RAM-HOL-SAM58CPKLN-CU
RAM-HOL-SAM58PCLU
RAM-HOL-SAM58PD2CLU
RAM-HOL-SAM58PD2KLU
RAM-HOL-SAM58PDCLU
RAM-HOL-SAM58PDKLU
RAM-HOL-SAM58PKLU

Accompanying Power Supplies

RAM-GDS-CHARGE-V7B1U



Test	Description
Vibration – operational	MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
Functional Shock - operational	MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth.
Pogo Pins – Cycle rating	Pogo pins rated to 100k cycles
USB Validation Protocol, Speed, Power	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
Power Supply Input Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
Power Supply Output Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Power Supply Load Test	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Regulatory Compliance	FCC, IC CE, RoHS, WEEE
Safety, Emission, Immunity (Ram Power Supply)	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark